Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/090,939	TAZAWA ET AL.	TAZAWA ET AL.
Examiner	Art Unit	Art Unit
Binh Q. Nguyen	2664	2664

SEARCHED					
Class	Subclass	Date	Examiner		
370	223	12/12/2005	BQN		
370	395.1	12/12/2005	BQN		
370	474	12/12/2005	BQN		
370	352	12/12/2005	BQN		
370	241	12/12/2005	BQN		
709	238	12/12/2005	BQN		
709	227	12/12/2005	BQN		
709	247	12/12/2005	BQN		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
EAST (US-GPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM-TDB), see more on search history.	12/12/2005	BQN
Consulted with Andrew Lee	12/12/2005	BQN